

Calculation of polarization sheet charge density

This teaching module shows how to calculate the polarization sheet charge density at the interface between AlGa_N electron blocking layer and a Ga_N spacer layer, pseudomorphically grown on relaxed AlGa_N, Ga_N, and GaIn_N templates.

Basic equations for spontaneous polarization

The spontaneous polarization is determined by the material composition. The values of the spontaneous polarization for the binary III-N materials are listed as follows [1]:

$$P_{\text{AlN}}^{\text{SP}} = -0.0898 \text{ C/m}^2$$

$$P_{\text{GaN}}^{\text{SP}} = -0.0339 \text{ C/m}^2$$

$$P_{\text{InN}}^{\text{SP}} = -0.0413 \text{ C/m}^2$$

In the case of ternary and quaternary III-N materials, the spontaneous polarization is expressed by using a second-order polynomial of the alloy composition [2].

$$P_{\text{Al}_x\text{Ga}_{1-x-y}\text{In}_y\text{N}}^{\text{SP}} = x P_{\text{AlN}}^{\text{SP}} + y P_{\text{InN}}^{\text{SP}} + (1 - x - y) P_{\text{GaN}}^{\text{SP}} + b_{\text{AlGaN}} x (1 - x - y) \\ + b_{\text{GaInN}} y (1 - x - y) + b_{\text{AlInN}} xy$$

The bowing parameters are listed as follows [3]:

$$b_{\text{AlGaN}} = +0.0191 \text{ C/m}^2$$

$$b_{\text{GaInN}} = +0.0378 \text{ C/m}^2$$

$$b_{\text{AlInN}} = +0.0709 \text{ C/m}^2$$

Basic equations for piezoelectric polarization

The piezoelectric polarization is determined by the induced strain on the material. The strain in an epitaxial layer pseudomorphically grown on a relaxed template is expressed as:

$$\varepsilon = \frac{a_{\text{template}} - a_{\text{epi}}}{a_{\text{epi}}}$$

The in-plane lattice constants of the relaxed binary III-N materials are listed as follows [4]:

$$a_{\text{AlN}} = 0.31095 \text{ nm}$$

$$a_{\text{GaN}} = 0.31986 \text{ nm}$$

$$a_{\text{InN}} = 0.35848 \text{ nm}$$

The in-plane lattice constants of the relaxed ternary and quaternary III-N materials can be calculated by using Vegard's law.

$$a_{\text{Al}_x\text{Ga}_{1-x-y}\text{In}_y\text{N}} = xa_{\text{AlN}} + ya_{\text{InN}} + (1 - x - y)a_{\text{GaN}}$$

The piezoelectric polarizations in binary III-nitrides are expressed as follows [2]:

$$P_{\text{AlN}}^{\text{PZ}}(\varepsilon) = -1.808 \varepsilon + 5.624 \varepsilon^2 \text{ [C/m}^2\text{]}, \text{ for } \varepsilon < 0$$

$$P_{\text{AlN}}^{\text{PZ}}(\varepsilon) = -1.808 \varepsilon - 7.888 \varepsilon^2 \text{ [C/m}^2\text{]}, \text{ for } \varepsilon > 0$$

$$P_{\text{GaN}}^{\text{PZ}}(\varepsilon) = -0.918 \varepsilon + 9.541 \varepsilon^2 \text{ [C/m}^2\text{]}$$

$$P_{\text{InN}}^{\text{PZ}}(\varepsilon) = -1.373 \varepsilon + 7.559 \varepsilon^2 \text{ [C/m}^2\text{]}$$

In the case of ternary III-nitrides, the piezoelectric polarization is calculated from the piezoelectric polarization of binary III-nitrides and Vegard's law:

$$P_{\text{A}_x\text{B}_{1-x}\text{N}}^{\text{PZ}}(\varepsilon) = x P_{\text{AN}}^{\text{PZ}}(\varepsilon) + (1 - x) P_{\text{BN}}^{\text{PZ}}(\varepsilon)$$

Basic equations for polarization sheet charge density

When an epitaxial layer, **A**, is pseudomorphically grown on a template, **T**, the polarization sheet charge density between two different layers can be expressed as:

$$\sigma = -(P_{\text{A}}^{\text{total}} - P_{\text{T}}^{\text{total}}) = -(P_{\text{A}}^{\text{SP}} + P_{\text{A}}^{\text{PZ}} - P_{\text{T}}^{\text{SP}} - P_{\text{T}}^{\text{PZ}})$$

When an epitaxial layer, **B**, is inserted between layer **A** and template **T**, the polarization sheet charge density between layer **A** and **B** can be expressed as:

$$\sigma = -(P_{\text{A}}^{\text{total}} - P_{\text{B}}^{\text{total}}) = -(P_{\text{A}}^{\text{total}} - P_{\text{T}}^{\text{total}}) + (P_{\text{B}}^{\text{total}} - P_{\text{T}}^{\text{total}})$$

Figure 1 shows the polarization sheet charge density between the GaN QB and GaInN QW (left-hand ordinate) and the AlGaIn EBL and GaN spacer (right-hand ordinate) pseudomorphically grown on ternary III-nitride templates (GaInN and AlGaIn).

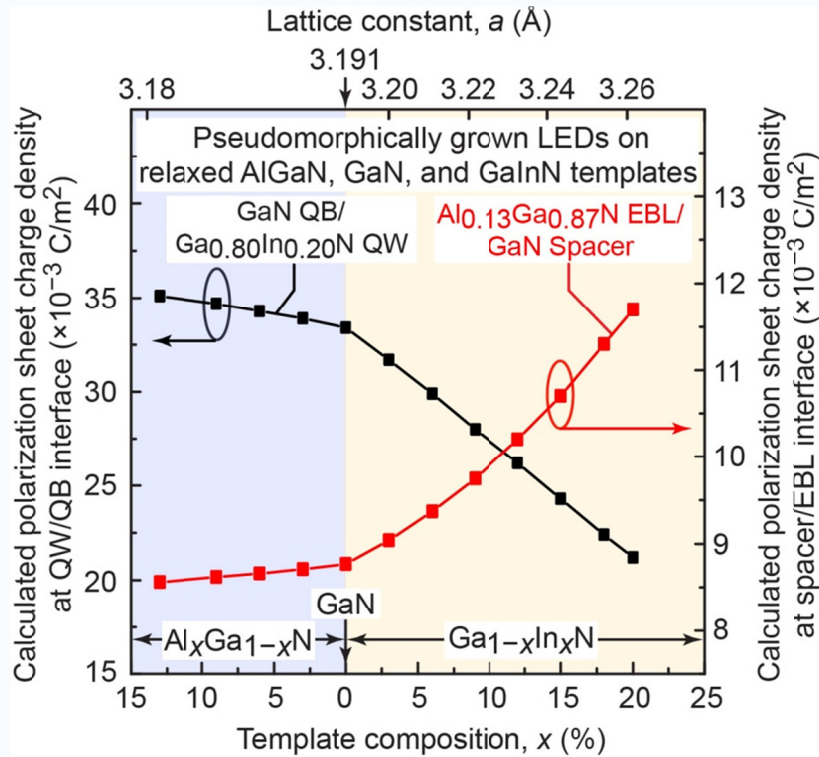


Figure 1: Relation between the template composition and the calculated polarization sheet charge densities at the interface between $\text{Ga}_{0.80}\text{In}_{0.20}\text{N}$ QW and GaN QB and between GaN spacer and $\text{Al}_{0.13}\text{Ga}_{0.87}\text{N}$ EBL. The active-region (including the EBL) layers are grown pseudomorphically on the templates and the templates are assumed to be relaxed.

References

- [1] F. Bernardini *et al.* “Accurate calculation of polarization-related quantities in semiconductors” *Phys. Rev. B* **63**, 193201 (2001)
- [2] F. Bernardini “Spontaneous and piezoelectric polarization: basic theory v. practical recipes” in J. Piprek (Ed.) *Nitride Semiconductor Devices: Principles and Simulation* (Wiley-VCH Verlag GmbH & Co. KGaA 2007)
- [3] F. Bernardini *et al.* “Nonlinear behavior of spontaneous and piezoelectric polarization in III-V nitride alloys”, *Phys. Stat. Sol. (a)* **90**, 65 (2002)
- [4] V. Fiorentini *et al.* “Evidence for nonlinear macroscopic polarization in III-V nitride alloy heterostructures” *Appl. Phys. Lett.* **80**, 1204 (2002)